

### **How to generate high quality tests for digital systems**

**Ubar, Raimund-Johannes; Aarna, Margit; Kruus, Helena; Raik, Jaan** 2004 International Semiconductor Conference : 27th edition, October 4-6, 2004, Sinaia, Romania : CAS 2004 proceedings. Volume 2 2004 / p. 459-462 : ill <http://dx.doi.org/10.1109/SMICND.2004.1403048>

### **Teaching advanced test issues in digital electronics**

**Ubar, Raimund-Johannes; Orasson, Elmet; Raik, Jaan;** Wuttke, Heinz-Dietrich Proceedings of the 6th IEEE International Conference on Information Technology Based Higher Education and Training : ITHET : July 7-9, 2005, Juan Dolio, Dominican Republic 2005 / p. S2B-1 - S2B-6 : ill <http://dx.doi.org/10.1109/ITHET.2005.1560318>